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FQS4900

Dual N & P-Channel, Logic Level MOSFET

General Description

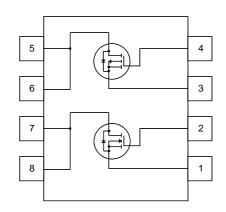
These dual N and P-channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. This device is well suited for high interface in telephone sets.

Features

- N-Channel 1.3A, 60V, $R_{DS(on)}$ = 0.55 Ω @ V_{GS} = 10 V $\begin{array}{c} \text{R}_{DS(on)} = 0.65~\Omega \quad @ \text{V}_{GS} = 5~\text{V} \\ \text{P-Channel -0.3A, -300V, } \text{R}_{DS(on)} = 15.5~\Omega \quad @ \text{V}_{GS} = -10~\text{V} \\ \text{R}_{DS(on)} = 16~\Omega \quad @ \text{V}_{GS} = -5~\text{V} \\ \end{array}$ • Low gate charge (typical N-Channel 1.6 nC)
- (typical P-Channel 3.6 nC)
- · Fast switching
- · Improved dv/dt capability





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		N-Channel	P-Channel	Units
V_{DSS}	Drain-Source Voltage		60	-300	V
I _D	Drain Current - Continuous (T _A = 25°C)		1.3	-0.3	Α
	- Continuous (T _A = 70°C)		0.82	-0.19	Α
I _{DM}	Drain Curent - Pulsed	(Note 1)	5.2	-1.2	Α
V _{GSS}	Gate-Source Voltage		± 20		V
dv/dt	Peak Diode Recovery dv/dt	(Note 2)	7.0	4.5	V/ns
P _D	Power Dissipation (T _A = 25°C)		2.0		W
	$(T_A = 70^{\circ}C)$		1.3		W
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	-	62.5	°C/W

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	N-Ch	60			V
DOO		$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	P-Ch	-300			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V				1	μА
		V _{DS} = 48 V, T _C = 55°C	N-Ch			10	μA
		V _{DS} = -300 V, V _{GS} = 0 V	- 0			-1	μΑ
		V _{DS} = -240 V, T _C = 55°C	P-Ch			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V	All			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V	All			-100	nA
On Cha	racteristics		- 1	I		11	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = 4V, I_{D} = 20 \text{ mA}$	N-Ch	1.0		1.95	V
00(11)	- care in carrein carries	$V_{DS} = 4V, I_{D} = -20 \text{ mA}$	P-Ch	-1.0		-1.95	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 0.65 A			0.39	0.55	Ω
DO(OII)		V _{GS} = 5 V, I _D = 0.65 A	N-Ch		0.46	0.65	Ω
		V _{GS} = -10 V, I _D = -0.15 A			11.2	15.5	Ω
		V _{GS} = -5 V, I _D = -0.15 A	P-CH		11.4	16	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 0.65 A	N-CH		1.7		S
953	Torward Transcorradictarios	$V_{DS} = -10 \text{ V}, I_{D} = -0.15 \text{ A}$	P-CH		0.6		S
Switchi	ng Characteristics						
$t_{d(on)}$	Turn-On Delay Time	N-Channel	N-Ch		5.7	21	ns
_		$V_{DD} = 30 \text{ V}, I_{D} = 1.3 \text{ A},$	P-Ch		10	30	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$	N-Ch		21	50	ns
+		P-Channel	P-Ch N-Ch		25 11	60 32	ns
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = -150 \text{ V}, I_D = -0.3 \text{ A},$	P-Ch		35	80	ns ns
t _f		$R_G = 25 \Omega$	N-Ch		17	45	ns
1	Turn-Off Fall Time		P-Ch		47	105	ns
Qg	Total Gate Charge	N-Channel	N-Ch		1.6	2.1	nC
3	-	$V_{DS} = 48 \text{ V}, I_{D} = 1.3 \text{ A},$	P-Ch		3.6	4.7	nC
Q_{gs}	Gate-Source Charge	$V_{GS} = 5 V$	N-Ch		0.28		nC
		P-Channel	P-Ch		0.42		nC
Q_{gd}	Gate-Drain Charge	$V_{DS} = -240 \text{ V}, I_{D} = -0.3 \text{ A},$ $V_{GS} = -5 \text{ V}$	N-Ch		0.82		nC
		VGS3 V	P-Ch		2.1		nC
	ource Diode Characteristics a		1	I		I	T
I _S	Maximum Continuous Drain-Source Did	ode Forward Current	N-Ch			1.3	A
		V -0VI 42A	P-Ch			-0.3	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_{S} = 1.3 \text{ A}$	N-Ch			1.5	V
	- I I I I I I I I I I I I I I I I I I I	$V_{GS} = 0 \text{ V, } I_{S} = -0.3 \text{ A}$	P-Ch			-4.0	

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 3. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$ 4. Essentially independent of operating temperature

Typical Characteristics: N-Channel

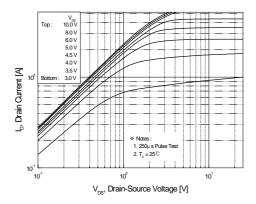


Figure 1. On-Region Characteristics

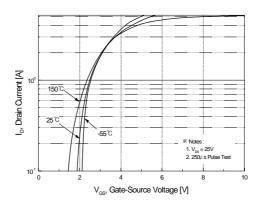


Figure 2. Transfer Characteristics

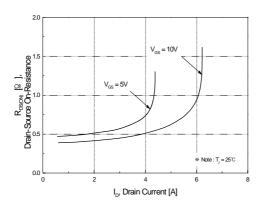


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

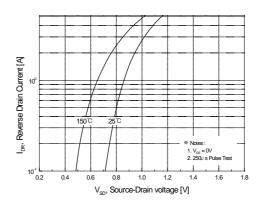


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

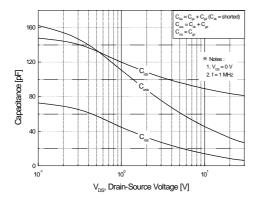


Figure 5. Capacitance Characteristics

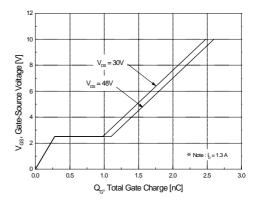


Figure 6. Gate Charge Characteristics

Typical Characteristics: N-Channel (Continued)

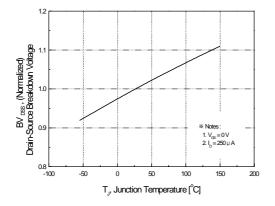
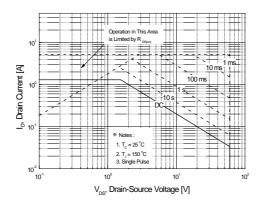


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



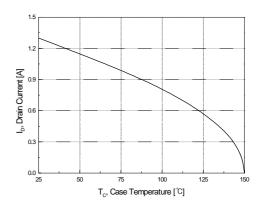


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

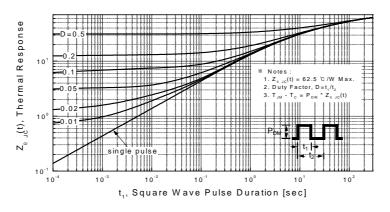


Figure 11. Transient Thermal Response Curve

Typical Characteristics: P-Channel (Continued)

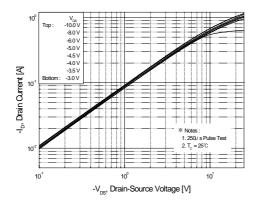


Figure 1. On-Region Characteristics

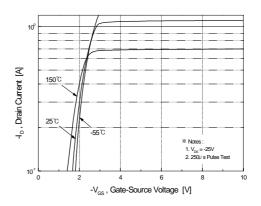


Figure 2. Transfer Characteristics

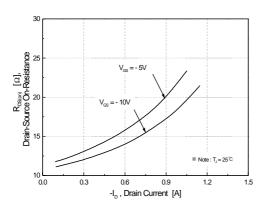


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

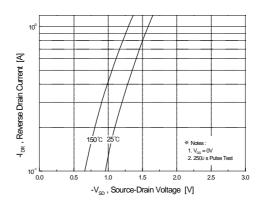


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

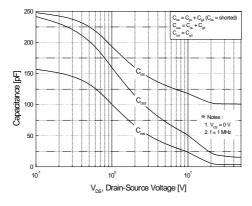


Figure 5. Capacitance Characteristics

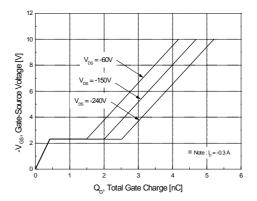


Figure 6. Gate Charge Characteristics

Typical Characteristics: P-Channel (Continued)

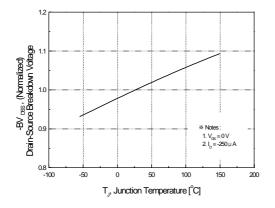


Figure 7. Breakdown Voltage Variation vs. Temperature

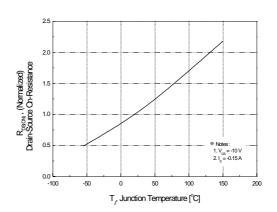


Figure 8. On-Resistance Variation vs. Temperature

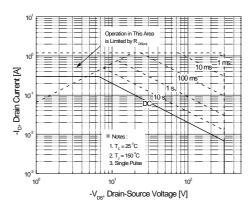


Figure 9. Maximum Safe Operating Area

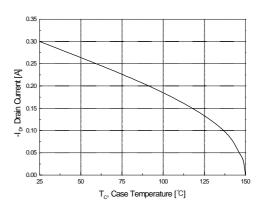


Figure 10. Maximum Drain Current vs. Case Temperature

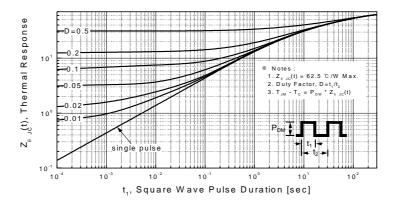
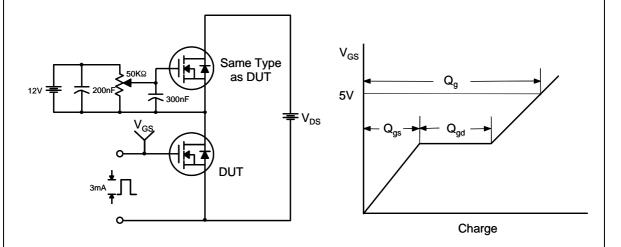
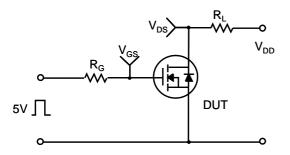


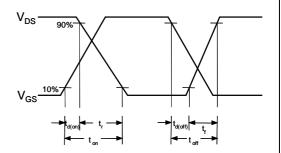
Figure 11. Transient Thermal Response Curve

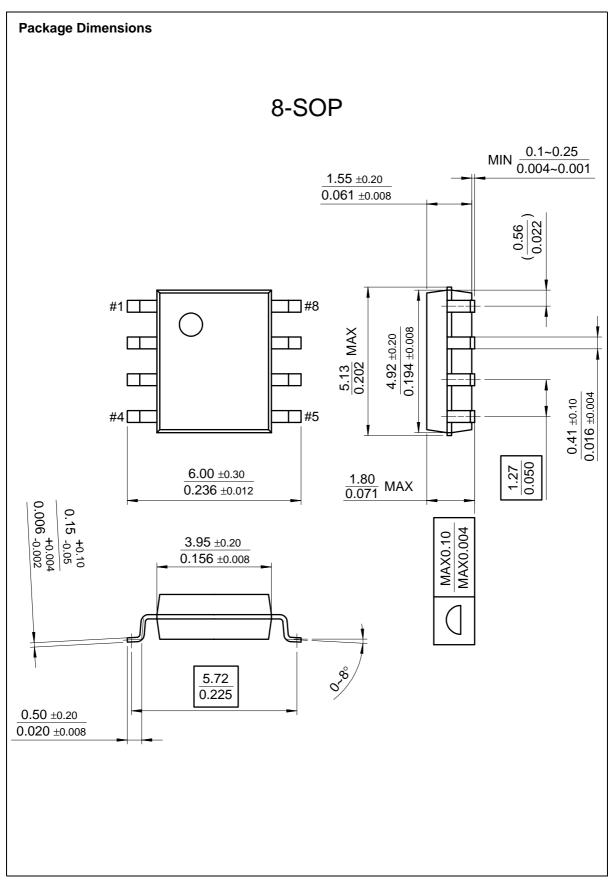
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms







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